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scket No.

292393US2PCT

IN THE UNITED SPATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Laurent PAIN

SERIAL NO:

10/582,791

GAU:

FILED:

June 14, 2006

EXAMINER:

FOR:

METHOD FOR REPAIRING ERRORS OF PATTERNS EMBODIED IN THIN LAYERS

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT						
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				FILING DATE June 14, 2006		GROUP	GROUP			
				U.S. PATENT DOCUMENTS						
EXAMINER		DOCUMENT	1		T	SUB	FII	ING DATE		
INITIAL		NUMBER	DATE	NAME	CLASS	CLASS		PROPRIA		
	AA	2003 039923	02-27-03	MANGAT, Pawitter et al.						
	AB	6 596 465	07-22-03	MANGAT, Pawitter Jit Singh et al.						
	AC	2003 027053	02-06-03	YAN, Péi-yang						
	AD	2002 122995	09-05-02	MANCINI, David P. et al.		!				
	AE	5 945 238	08-31-99	HUGGINS, Alan H. et al.	!		<u> </u>			
	AF	5 985 518	11-16-99	HUGGINS, Alan H. et al.	!	!				
	AG	5 953 577	09-14-99	HUGGINS, Alan H. et al.		!				
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			FO	DREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO					
	AO	60 142518	12-03-85	JP (with English abstract)				NO		
	AP									
	ĄQ									
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			•	(Including Author, Title, Date, Pertinent		•				
	AW	LIPP, S.et al.," A Comparison of Focused Ion Beam and Electron Beam Induced Deposition Processes", Microelectron. Reltab., Vol. 36, No. 11/12, pgs. 1779-1782, 1996.								
	AX	WARD, B.W.et al.," Repair of Photomasks with Focussed Ion Beams", SPIE, Vol. 537, pgs. 110-116, 1985.								
	AY									
	AZ			Additional References sheet(s) attached						
Examiner						Date Considered				
*Examiner: In	itial if r	reference is considered,	, whether or no	ot citation is in conformance with MPEP 60)9; Draw lir	ne through	citation if	f not in		



U.S. PCT Application Serial No: 10/582,791

Filed: June 14, 2006

Laurent PAIN

بالمغرور والمرتواه

Docket No. 292393US2PCT

STATEMENT OF RELEVANCY

- 1) References AA-AG and AO have been cited in the International Search Report. A copy of these references is being submitted herewith.
- 2) References have been cited in the corresponding Search Report. A copy of these references is being submitted herewith.
- 3) References are discussed in the specification. A copy of these references is being submitted herewith.
- 4) References AW-AX are additional prior art known to Applicant. A copy of these references is being submitted herewith.